## Contents

<table>
<thead>
<tr>
<th>Section</th>
<th>Page</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>Agenda</strong></td>
<td>4</td>
</tr>
<tr>
<td><strong>Keynote Speakers</strong></td>
<td>6</td>
</tr>
<tr>
<td><strong>Technical Sessions</strong></td>
<td></td>
</tr>
<tr>
<td>Software Development Techniques</td>
<td>7</td>
</tr>
<tr>
<td>Data Acquisition Systems</td>
<td>8</td>
</tr>
<tr>
<td>Automated Test Systems</td>
<td>9</td>
</tr>
<tr>
<td>Embedded Systems</td>
<td>10</td>
</tr>
<tr>
<td>From RF Design to Wireless Test</td>
<td>11</td>
</tr>
<tr>
<td>Hands-On Workshops</td>
<td>12</td>
</tr>
<tr>
<td>Exhibition</td>
<td>13</td>
</tr>
<tr>
<td>NI Product Showcase</td>
<td>14</td>
</tr>
<tr>
<td>Training and Certification</td>
<td>15</td>
</tr>
<tr>
<td>Technical Sales and Support</td>
<td>16</td>
</tr>
</tbody>
</table>

## Sponsors
Dear Colleague,

Welcome to NIDays San Jose. As a showcase for the latest technology and innovation from the region’s top engineers and scientists, this year’s event promises to be our best yet, with more than 40 technical sessions, advanced training, networking, and an exhibit area featuring NI and partner solutions and services.

But the NIDays experience goes far beyond professional development and outreach. Today you’ll be joining fellow researchers, engineers, innovators, and educators to learn how to use LabVIEW system design software and modular hardware to tackle the world’s greatest engineering challenges.

In this spirit of grand ambition and true collaboration, see how you and NI will redefine innovation, build the technology that makes things work, and ultimately impact society through awe-inspiring, accessible applications.

So immerse yourself in all NIDays has to offer—from the hottest trends in designing test, measurement, and embedded systems to the technical sessions that advance your professional development.

Thanks to the sponsors, exhibitors, and you for being a part of this world-class event.

Best regards,

Richard McDonell
Technical Director, Americas
National Instruments
<table>
<thead>
<tr>
<th>Time</th>
<th>Software Development Techniques</th>
<th>Data Acquisition Systems</th>
<th>Automated Test Systems</th>
</tr>
</thead>
<tbody>
<tr>
<td>8:00 a.m.</td>
<td>Registration and Continental Breakfast</td>
<td>Room 230A</td>
<td>Room 231A</td>
</tr>
<tr>
<td>9:00 a.m.</td>
<td>Welcome and Event Kick-off</td>
<td>Room 231B</td>
<td></td>
</tr>
<tr>
<td>9:30 a.m.</td>
<td>Using Python with LabVIEW and TestStand</td>
<td>Do Engineering: Connecting Teaching, Research, and Industry</td>
<td>Best Practices for Building Board-Level Automated Test Stations</td>
</tr>
<tr>
<td>11:00 a.m.</td>
<td>Data Communication Methods for Embedded Systems</td>
<td>DAQ Advanced: Digging Deep Into NI-DAQmx Functions and Property Nodes</td>
<td>Maximizing ATE Hardware Abstraction With TestStand</td>
</tr>
<tr>
<td>11:45 a.m.</td>
<td>Lunch and Exhibition</td>
<td></td>
<td></td>
</tr>
<tr>
<td>12:15 p.m.</td>
<td>Lunch Keynote: Using a Platform-Based Approach to Create the Internet of Things</td>
<td>Jamie Smith, Director of Product Marketing, Embedded Systems, NI</td>
<td></td>
</tr>
<tr>
<td>1:15 p.m.</td>
<td>Break and Exhibition</td>
<td></td>
<td></td>
</tr>
<tr>
<td>1:45 p.m.</td>
<td>Web Development With the LabVIEW Web Server</td>
<td>Practical Advice for Ensuring Accurate Electrical Measurements</td>
<td>Keep Your PXI System Busy: Optimize RF Automation With NI-RFmx</td>
</tr>
<tr>
<td>2:30 p.m.</td>
<td>Extending Your Skills to the LabVIEW RIO Architecture</td>
<td>Top Software Tips for Deployed or Distributed DAQ Systems</td>
<td>Characterize and Test RADAR Pulses</td>
</tr>
<tr>
<td>3:15 p.m.</td>
<td>A Discussion About the Future of LabVIEW</td>
<td>CompactRIO or CompactDAQ? Could You Repeat the Question?</td>
<td>Built for Speed: How to Optimize SMUs for High-Throughput DC Testing</td>
</tr>
<tr>
<td>4:00 p.m.</td>
<td>Break and Exhibition</td>
<td></td>
<td></td>
</tr>
<tr>
<td>4:30 p.m.</td>
<td>Closing Keynote: Trillions to Primordial: What Happens When Things Wake Up?</td>
<td>Mickey McManus, Visiting Research Fellow at Autodesk, Chairman and Principal at MAYA Design</td>
<td></td>
</tr>
</tbody>
</table>

**From RF Design to Wireless Test**

**Keynotes**

**Breaks/Meals**
<table>
<thead>
<tr>
<th>Embedded Systems</th>
<th>Hands-On Workshops</th>
<th>From RF Design to Wireless Test</th>
</tr>
</thead>
<tbody>
<tr>
<td>Room 232</td>
<td>Room 230B</td>
<td>Room 230C</td>
</tr>
<tr>
<td></td>
<td>Room 233</td>
<td></td>
</tr>
</tbody>
</table>

**Registration and Continental Breakfast**

**Welcome and Event Kick-off**

- *Is Online Condition Monitoring Right for Me?*
- *Introduction to LabVIEW for Instrumentation*
- *Introduction to LabVIEW and Data Acquisition Applications*
- *Prototyping with Software Defined Radio for Industry, Academic, and Defense Applications*
- *Programming CompactRIO with LabVIEW Real-Time (Part 1)*
- *5G: Prototyping New 802.11 and Cellular Waveforms in LabVIEW Communications*
- *Programming CompactRIO with LabVIEW FPGA (Part 2)*
- *Accelerating RF Transceiver Validation with SDR-Based Record & Playback*

**Lunch and Exhibition**

**Lunch Keynote:** Using a Platform-Based Approach to Create the Internet of Things  
*Jamie Smith,* Director of Product Marketing, Embedded Systems, NI

**Break and Exhibition**

- *Introducing New Technologies to Enable the Industrial Internet of Things*
- *Introduction to LabVIEW for Instrumentation*
- *Introduction to LabVIEW and Data Acquisition Applications*
- *Strategies to Optimize Product Test for Wearable Devices*
- *Gain Accuracy and Flexibility Through Tight Vision and Motion Integration*
- *Building an Automated Test System With TestStand and the PXI Platform*
- *Programming CompactRIO with LabVIEW Real-Time (Part 1)*
- *RFIC Testing from R&D to Production: Choosing a Test Approach to Reduce the Cost of Test*
- *Choosing a Software Architecture for Your Next Embedded Application*
- *Programming CompactRIO with LabVIEW FPGA (Part 2)*
- *Addressing Modern RF Power Amplifier Test Requirements*

**Break and Exhibition**

**Closing Keynote:** Trillions to Primordial: What Happens When Things Wake Up?  
*Mickey McManus,* Visiting Research Fellow at Autodesk, Chairman and Principal at MAYA Design  
*(Prize Drawings)*
Keynote Speakers

Lunch Keynote | 12:15–1:15 p.m.

Using a Platform-Based Approach to Create the Internet of Things

**Jamie Smith**, Director of Product Marketing, Embedded Systems, NI

Together, you and NI are using a platform-based approach to overcome escalating complexity and create the Internet of Things (IoT). Join Jamie as he explores how the NI vision is empowering engineers and scientists to make this trend a reality.

**Rosanna Martinez**, Regional Marketing Manager, Americas, NI

Join Rosanna as she examines the latest advances in the NI platform and the ways you are using them to speed up test, reach measurement decisions faster, and enable smarter machines in the IoT. This keynote features live demonstrations of application examples and the technology powering real-world IoT systems such as wireless test, data management, condition monitoring, and communications system design.

Closing Keynote | 4:30–5:30 p.m.

Trillions to Primordial: What Happens When Things Wake Up?

**Mickey McManus**, Visiting Research Fellow at Autodesk, Chairman and Principal at MAYA Design

We are fast approaching an era of unprecedented complexity as more and more things, environments, and systems become interconnected. Often called the Internet of Things, this trend is leading to a world with trillions of devices that communicate with each other and with us. Witness how the Internet of Things, combined with trends in machine learning and digital manufacturing, is creating greater possibilities for innovation including inspiring a team to redesign the classic hot rod for the 21st century using Autodesk Dreamcatcher and the NI platform.

Prize Drawing

Attend the closing keynote to participate in a prize drawing featuring prizes such as a LEGO® MINDSTORMS®, iPad, myRIO, LabVIEW software, and a full-conference pass to NIWeek 2016.
Explore new technologies and techniques to help you build IoT-ready software applications, increase productivity, and ensure system flexibility in your designs.

**Using Python with LabVIEW and TestStand**
9:30 a.m. | Room 230A

Is there a way to call NI hardware and software from a top-level Python script? What if I like using LabVIEW and TestStand for some parts of my application, but want to reuse a Python script for DUT control or analysis? Learn about the different ways you can use Python with NI hardware and software, and discuss how to choose the right tool for the challenge you are solving.

**Best Practices for Saving Measurement Data**
10:15 a.m. | Room 230A

You collect data to make decisions. However, an inefficient file format may cause problems when you analyze your data. The key to choosing the right file format, such as TDMS, for your application involves considering your current system requirements as well as ways you can adapt the file for future application needs. At this session, hear how to select a file format; organize metadata; and analyze, report, and share your results.

**Data Communication Methods**
11:00 a.m. | Room 230A

Coordinating data between their embedded controllers and other nodes in the system is identified by NI customers as one of the top challenges in embedded system design and is crucial for IoT applications. In this session, learn about effective distributed communication architectures between targets running LabVIEW while focusing on network published shared variables and network streams.

**Web Development With the LabVIEW Web Server**
1:45 p.m. | Room 230A

Integrating web technology into a LabVIEW application can be daunting, so begin your learning journey by building on the basics, from the LabVIEW web server, HTTP, HTML, JavaScript, and AJAX to JavaScript Libraries like Google Graphs. Walk through specific examples to learn these concepts and explore the LabVIEW Web Development Community to review these examples on your own and continue your learning journey.

**Extending Your Skills to the LabVIEW RIO Architecture**
2:30 p.m. | Room 230A

Have you used LabVIEW for your desktop and are now considering the LabVIEW Real-Time Module or LabVIEW FPGA Module and embedded hardware for your next project? Though your LabVIEW skills will transfer to programming embedded systems, you can learn 10 new concepts specific to the LabVIEW RIO architecture that can extend your skills to successfully make the transition.

**A Discussion About the Future of LabVIEW**
3:15 p.m. | Room 230A

LabVIEW has helped engineers across almost every region, market, and industry make a marked improvement to their everyday productivity as it relates to automating measurements. At this session, learn about the improvements in the latest version of LabVIEW, LabVIEW 2015, and explore where NI continues to invest in its software platform.
Sessions

Data Acquisition Systems

Build your knowledge of data acquisition systems with in-depth product sessions and software development best practices.

Do Engineering: Connecting Teaching, Research, and Industry
9:30 a.m. | Room 231A

The IoT is having a profound impact on the discipline of system design. Product design, manufacturing, and infrastructure are all affected by this technology evolution. Collaboration with industry is essential for academic institutions to deliver impactful research- and workforce-ready students to this new interconnected future. Hear more about how NI is partnering with educators and academic researchers to turn the vision of IoT into reality.

New Hardware Technologies for DAQ Applications
10:15 a.m. | Room 231A

Whether your application involves taking a few voltage measurements, a few dozen sensor measurements, or even a few hundred synchronized measurements, NI is constantly developing new technology and releasing new products that improve your ability to meet application requirements. At this session, explore the major DAQ product lines for engineers less familiar with the NI platform before looking in detail at new hardware releases, their enabling technology, and their application use cases.

DAQ Advanced: Digging Deep Into NI-DAQmx Functions and Property Nodes
11:00 a.m. | Room 231A

From high-speed file I/O frameworks to custom analog clocking, hear about some of the powerful yet little known features in the NI-DAQmx software driver that you can use for your next application.

Practical Advice for Ensuring Accurate Electrical Measurements
1:45 p.m. | Room 231A

Every physical system component increases signal error, noise, and uncertainty. Thankfully, you have many established techniques for minimizing your DAQ system’s exposure to these predigitization errors. At this session, hear best practices for shielding, gain, noise reduction, grounding, and connectivity that help increase the accuracy of your measurement.

Top Software Tips for Deployed or Distributed DAQ Systems
2:30 p.m. | Room 231A

When you deploy systems into the field for distributed or in-vehicle applications, errors and inaccuracies can grow into expensive and sometimes safety-critical failures. At this session, hear from experienced engineers as they offer their top tips for the reliable acquisition, analysis, storage, and management of measurement data for deployed applications.

CompactRIO or CompactDAQ? Could You Repeat the Question?
3:15 p.m. | Room 231A

CompactRIO and CompactDAQ are similar in many ways, from the form factor they share to the C Series modules they use. But the applications they are optimized for have different requirements. At this session, learn which platform is right for your needs and explore new products to help you get the job done.
Automated Test Systems
Learn from test industry experts about the latest tools and techniques to help you successfully build better automated test systems with PXI and modular instruments.

**t** Best Practices for Building Board-Level Automated Test Stations
**9:30 a.m. | Room 231B**
This session, presented by Alliance Partner Circuit Check Inc., explores steps for configuring PCBA test stations to address interfacing from the measurement instrument to the device under test I/O pin. Topics include methods of connecting receivers to PXI instruments, approaches to applying force to hold a PCBA against spring test probes, and the differences between mechanical and vacuum-based solutions. It also features videos of single unit and fully automated PCBA test systems.

**n** Create Without Limits: 4 Ways to Customize Your Software-Designed Instrument
**10:15 a.m. | Room 231B**
Engineers are using software-designed instruments to reduce test time, increase test throughput, overcome obsolescence challenges, and perform innovative tests. At this session, focus on four key software approaches for developing code on software-designed instruments: (1) using standard instrument drivers, (2) enhancing instrument driver functionality with FPGA extensions, (3) leveraging NI-installed sample projects, and (4) reusing application-specific IP from the NI Community.

**d** Keep Your PXI System Busy: Optimize RF Automation With NI-RFmx
**1:45 p.m. | Room 231B**
In any RF automated test application, optimizing system resources can be challenging. At this session, review the NI-RFmx measurement API and discover how you can use it with NI PXI RF instrumentation to easily build a test program that keeps resources busy and thus reduces overall test time.

**d** Characterize and Test RADAR Pulses
**2:30 p.m. | Room 231B**
Walk through the design and test of a complete RADAR system. Discover how to generate and accurately analyze low-phase noise RADAR pulses. Examine in detail common pulses like CW, narrowband, and wideband FM chirps in the Ku, K, and Ka bands.

**t** Built for Speed: How to Optimize SMUs for High-Throughput DC Testing
**3:15 p.m. | Room 231B**
High-precision DC measurements frequently need a long measurement cycle to ensure proper signal integrity. However, many of these measurements are often unnecessarily throttled because of software overhead, long settling times, or inefficient measurement engine use. At this session, discover how to optimize source measure units (SMUs) for test throughput while maintaining an acceptable level of precision.

**d** Maximizing ATE Hardware Abstraction With TestStand
**11:00 a.m. | Room 231B**
If you maintain multiple test systems, develop test sequences for a wide range of products, or deal with the hassles of instrumentation or platform changes, implementing a hardware abstraction layer (HAL) can save you time, money, and frustration by reducing the impact of hardware changes, maximizing code reuse, and minimizing development effort. This session, by Alliance Partner Bloomy, dives deeply into the concepts and benefits of hardware abstraction and uses TestStand to identify and demonstrate the major components of a HAL through real-world examples to help you maintain ATE for years to come.
Sessions

Embedded Systems

Discover a better way to design advanced control and monitoring systems that maximize flexibility, reduce time to market, and minimize cost and risk.

Is Online Condition Monitoring Right for Me?
9:30 a.m. | Room 232
Do you want to reduce downtime, increase efficiency, or decrease waste? Do you manufacture industrial equipment, machines, or infrastructure or do you work at a manufacturing, generation, distribution, or processing plant? If so, you may benefit from online condition monitoring (CM). At this session by Alliance Partner Viewpoint Systems, and Allied Reliability, get an overview of when to consider CM, what you can monitor, which information you can produce, and how to get started.

Introducing New Technologies to Enable the Industrial Internet of Things
1:45 p.m. | Room 232
In this session, learn about the new NI technology for embedded control and monitoring applications. Products include the latest CompactRIO and Single-Board RIO controllers, the new Controller for FlexRIO, and the latest C Series I/O modules. These devices incorporate the most up-to-date technology and provide new I/O points to offer you innovative and advanced functionality that can increase your productivity and system performance. Attend this session to see some of this new technology in action and learn how it can enable your next application.

Processing at the Edge: Why a Platform-Based Approach Is Ideal for the Industrial Internet of Things
10:15 a.m. | Room 232
Are you ready to implement the Industrial Internet of Things (IIoT)? This technology revolution is more than just a vision or a trend; it is here today and here to stay. In this session, learn about the incredible opportunities being created by this migration toward smarter devices, processes, and infrastructure. Discuss the fundamentals of the IIoT, which begins at “the edge,” and how the LabVIEW reconfigurable I/O architecture can help you design, prototype, and deploy complex embedded control and monitoring systems for IIoT applications.

Gain Accuracy and Flexibility Through Tight Vision and Motion Integration
2:30 p.m. | Room 232
Machine vision and advanced motion control are integral components of smart automation. These two components can increase throughput and allow you to build highly efficient modern machines. While state-of-the-art motion control systems make the design of integrated mechatronics systems possible, machine vision allows for non-invasive inspection and measurements. By integrating the motion and vision components on a single embedded system, leading machine builders are able to rapidly build the next generation of smart machines. Learn how you can use these technologies to achieve benefits such as increased precision and accuracy, faster material handling, and easy adaptation to new products and processes.

Meet the Other Half of Your Embedded R&D Team
11:00 a.m. | Room 232
Developing a reliable custom embedded solution from the ground up requires a lot of expertise, time, effort, and validation. NI offloads most of the up-front work and expertise needed by developing platform-based products for you to build on. Thus by choosing NI, you are extending your R&D team. In this session, get insight into the design practices and validation efforts of the NI R&D team and explore the extensive testing of NI’s embedded platforms to build your confidence in using NI tools for your applications.

Choosing a Software Architecture for Your Next Embedded Application
3:15 p.m. | Room 232
Developing software for embedded applications can be challenging. The real challenge often lies in processes like connecting that logic to I/O, integrating the application into an existing system, and ensuring that the application runs properly for months or years at a time. These projects also frequently encounter logistical challenges such as supporting multideveloper teams with tight time-to-market pressures. At this session, discover how a good architecture can help address these issues and review your different architecture options.
From RF Design to Wireless Test

Prototyping with Software Defined Radio for Industry, Academic, and Defense Applications
9:30 a.m. | Room 233

Advancements in Software Defined Radio technology are making wireless more accessible than ever before, benefiting industry, academia, and defense applications. In this session, we share how you can leverage a common software defined radio platform and choose the right software tool flow to design, prototype, and deploy SDR-based systems. Topics include designing new waveforms, prototyping high channel count systems, deployed spectrum monitoring, educational teaching solutions, and 5G research.

Strategies to Optimize Product Test for Wearable Devices
1:45 p.m. | Room 233

Presented by VI Engineering. One of the fastest growing markets, wearable devices encompass fitness, fashion, and health care. Most of these companies face stiff price competition and challenges such as lowering the cost of manufacturing high-quality devices in mass quantities. At this session, examine strategies that reduce both the upfront and recurring costs of test in the wearable device market while providing the necessary functional and RF test coverage at PCBA and device levels.

RFIC Testing from R&D to Production: Choosing a Test Approach to Reduce the Cost of Test
2:30 p.m. | Room 233

With the explosion of wireless technology, engineers are increasingly required to transition RFIC’s from R&D to production test more quickly - and at a lower cost. Come learn how NI tools and systems are helping engineers reduce both the cost of test and time to market. In this session we will review some of the key technologies required for testing RFICs in R&D - such as envelope tracking (ET) and digital predistortion (DPD). In addition, this session will introduce new features in the NI Semiconductor Test System that are used for production test cell integration.

Accelerating RF Transceiver Validation With SDR-Based Record & Playback
11:00 a.m. | Room 233

The many recent advances in software-defined radio (SDR) give RF product and system developers numerous cost-effective options for monitoring, recording and playing back authentic spectrum to advance their RF and GNSS transceiver designs and shorten validation cycles. In this session, NI Alliance Partner Averna will present the concept of an SDR-based record-and-playback solution and discuss various platform options, ranging from a portable laptop configuration to a VST-based system capable of capturing more than 200 MHz of simultaneous bandwidth.

RFIC Testing from R&D to Production: Choosing a Test Approach to Reduce the Cost of Test
2:30 p.m. | Room 233

With the explosion of wireless technology, engineers are increasingly required to transition RFIC’s from R&D to production test more quickly - and at a lower cost. Come learn how NI tools and systems are helping engineers reduce both the cost of test and time to market. In this session we will review some of the key technologies required for testing RFICs in R&D - such as envelope tracking (ET) and digital predistortion (DPD). In addition, this session will introduce new features in the NI Semiconductor Test System that are used for production test cell integration.

Addressing Modern RF Power Amplifier Test Requirements
3:15 p.m. | Room 233

The drive for high energy efficiency, multi-band LTE RF transmitters has led many designers to look beyond traditional fixed voltage supply RF power amplifiers. In this session we will review the basic concepts of one approach to address this issue, envelope tracking, and highlight some of the challenges to testing such systems. NewEdge Signal Solutions, a supplier of multi-band RF front end solutions for next generation wireless communications, will present on how they have solved challenges for small cell and infrastructure applications using NI platform.
**Hands-On Workshops**

Test-drive NI measurement, test, and control products with short, introductory hands-on sessions.

**Introduction to LabVIEW for Instrumentation**
9:30 a.m., 1:45 p.m. | Room 230B

Get an introduction to using LabVIEW for instrumentation by exploring the key benefits of LabVIEW for automated test. Also use the PXI platform and modular instruments in the exercises.

**Build an Automated Test System**
With TestStand and the PXI Platform
10:15 a.m., 2:30 p.m. | Room 230B

This hands-on session provides an introduction to developing an automated test system using NI's test solution to increase test development productivity and reduce overall costs. Learn to perform a functional test on multiple units under test using ready-to-run test management software, TestStand, paired with a PC-based modular instrumentation platform, PXI.

**Introduction to LabVIEW and Data Acquisition Applications**
9:30 a.m., 1:45 p.m. | Room 230C

This session, geared toward new DAQ users and those wanting to evaluate LabVIEW, explores how to program a measurement system to meet application-specific needs. Discover how to connect and acquire signals, perform inline analysis and file I/O, and build a rich user interface.

**Programming CompactRIO**
With LabVIEW Real-Time (Part 1)
10:15 a.m., 2:30 p.m. | Room 230C

Learn how to quickly build and deploy embedded monitoring and control applications using CompactRIO and the LabVIEW Real-Time Module. Also explore LabVIEW Real-Time features that increase flexibility and integration with the FPGA when programming with the RIO Scan Interface (aka Scan Mode).

**Programming CompactRIO**
With LabVIEW FPGA (Part 2)
11:00 a.m., 3:15 p.m. | Room 230C

Take advantage of the power of reconfigurable FPGAs for custom timing/triggering, inline signal processing, and fast closed-loop control. In this hands-on session, explore the basics of customizing CompactRIO with LabVIEW FPGA Module programming. Attendees should have basic LabVIEW and LabVIEW Real-Time knowledge.
### Exhibitors

<table>
<thead>
<tr>
<th>Exhibitor</th>
<th>Booth Number</th>
</tr>
</thead>
<tbody>
<tr>
<td>Acquired Data Solutions</td>
<td>918</td>
</tr>
<tr>
<td>Appando</td>
<td>916B</td>
</tr>
<tr>
<td>Averna</td>
<td>908</td>
</tr>
<tr>
<td>Ball Systems, Inc</td>
<td>802</td>
</tr>
<tr>
<td>B&amp;A Engineering Systems, Inc</td>
<td>904A</td>
</tr>
<tr>
<td>Bloomy</td>
<td>609B</td>
</tr>
<tr>
<td>Circuit Check, Inc</td>
<td>902</td>
</tr>
<tr>
<td>Cyth Systems, Inc</td>
<td>601 and 601B</td>
</tr>
<tr>
<td>Dynamic Test Solutions Asia</td>
<td>605</td>
</tr>
<tr>
<td>Everett Charles Technologies, LLC</td>
<td>808</td>
</tr>
<tr>
<td>GuideTech</td>
<td>904B</td>
</tr>
<tr>
<td>IEEE RAS</td>
<td>603</td>
</tr>
<tr>
<td>JKI</td>
<td>705</td>
</tr>
<tr>
<td>Kistler Instrument Corp.</td>
<td>619</td>
</tr>
<tr>
<td>MAC Panel Company</td>
<td>615</td>
</tr>
<tr>
<td>Mouser Electronics, Inc.</td>
<td>617A</td>
</tr>
<tr>
<td>NI Training and Certification</td>
<td>912</td>
</tr>
<tr>
<td>OPAL-RT</td>
<td>607</td>
</tr>
<tr>
<td>PCB Piezotronics</td>
<td>709</td>
</tr>
<tr>
<td>RTI</td>
<td>609A</td>
</tr>
<tr>
<td>Seica Inc.</td>
<td>914</td>
</tr>
<tr>
<td>Solution Sources Programming</td>
<td>707</td>
</tr>
<tr>
<td>TDK - Lambda Americas High Power Division</td>
<td>804</td>
</tr>
<tr>
<td>Verifide Tech Inc</td>
<td>703</td>
</tr>
<tr>
<td>VI Engineering</td>
<td>916A</td>
</tr>
<tr>
<td>Viewpoint Systems</td>
<td>613 and 900A</td>
</tr>
<tr>
<td>Virginia Panel Corporation</td>
<td>906</td>
</tr>
<tr>
<td>Wineman Technology, Inc.</td>
<td>617B</td>
</tr>
<tr>
<td>Winsoft Inc.</td>
<td>806</td>
</tr>
</tbody>
</table>
Visit the NIDays exhibition floor to see demonstrations of the latest NI hardware and software products. Stop by our more than 20 exhibitor booths, speak with industry experts about your applications, and watch them demonstrate their latest product and service offerings designed to help solve your engineering challenges.

Automated Test Systems
See how NI is redefining instrumentation with open software and modular hardware. Covering a range of applications in wireless and consumer electronics test, this exhibition features leading companies who want to show you how they are using PXI, LabVIEW, and TestStand to meet today’s test challenges while reducing their total cost of test.

Embedded Systems
As the Internet of Things expands, control and monitoring systems for the Industrial Internet of Things (IIoT) are getting more complex, taking longer to complete, and increasing in total cost of design. Discover a better way to design advanced control and monitoring systems that maximize flexibility, reduce time to market, and minimize cost and risk. Explore the IIoT landscape and check out some of the new features and releases in the NI embedded platforms.

Software
See multiple applications in action that illustrate the power and flexibility of LabVIEW and explore what’s new in LabVIEW 2015.

Data Acquisition Systems
Discover the flexibility of the CompactDAQ platform for a variety of sensor measurements and data-logging applications. Also interact with NI’s new radial approach to benchtop instrumentation, VirtualBench, which includes five instruments in one device.

Academic Teaching
Learn about the education platforms to “do engineering” with tools that prepare students to become the innovators of tomorrow.
Training and Certification

Gain the Skills You Want, Build the Code You Need.

Reduce Development Time and Costs, Learn Faster, and Increase Productivity
With extensive options for new and experienced users, NI has a course for you. Whether it’s a course at a local facility, on-site at your office, in a virtual classroom, or self-paced online, you select the delivery format to accommodate your time constraints, budget, and personal preferences. Learn the way YOU want to learn!
Visit ni.com/training and browse our course offerings.

Validate Your Expertise
Join the nearly 20,000 certified professionals worldwide who demonstrate their skills with NI products. Differentiate yourself and inspire confidence in managers, peers, and customers.
Visit ni.com/training/certification and explore NI certifications.

NIDays Attendee Exclusive Discount
NIDays attendees get 50 percent off instructor-led classes and certification exams. This offer is valid for 90 days after the event.
Call 866-337-5918 or email training.usca@ni.com for more information.
Technical Sales and Support

NI operates a world-class technical sales and support organization that is dedicated to ensuring your success with NI hardware and software platforms.

Our local team is organized to help you quickly and efficiently obtain the support you need for any project. Your company has a dedicated liaison. Refer to the names below to determine your primary local contact.

Your local NI contacts offer an agile, cross-functional team of product and industry experts. Their ability to draw on the collective knowledge and expertise of our local and Austin-based organizations guarantees you the best support for your project no matter what the challenge—whether it is technical or business related.

Thank you for choosing NI. We look forward to working with you.

California

Kyle Mozdyn
Academic Field Engineer
Southern California
kyle.mozdym@ni.com
213 973 7356

Glenn Manlongat
Academic Field Sales Engineer
Northern California
glenn.manlongat@ni.com
415 735 4536

Ingo Földvári
Academic Program Manager
California
ingo.foldvari@ni.com
760 691 0877

Conan McHugh
Regional Sales Director
West US
conan.mchugh@ni.com
650 722 6347

Thaison Verasiri
Field Engineer - Consumer Electronics
Northern California
thaison.verasiri@ni.com
408 334 8523

Arves Stolpe
District Sales Manager - Consumer Electronics
Southern California
arves.stolpe@ni.com
619 385 0333

Adam Wooderson
District Sales Manager - Consumer Electronics and Semiconductor
Northern California
adam.wooderson@ni.com
916 765 85280

Dave Thompson
District Sales Manager
Greater Los Angeles
dave.thompson@ni.com
310 701 9535

Zach Collins
District Sales Engineer
Greater Los Angeles
zach.collins@ni.com
626 372 0925

Chris Grabski
Field Engineer - San Francisco and Peninsula
Northern California
chris.grabski@ni.com
408 497 9739

Maggie Shaughnessy
Field Engineer - Sacramento, Reno, and Central Valley
Northern California
maggie.shaughnessy@ni.com
916 203 1254

Paul Bouagnon
District Sales Manager
Greater Los Angeles
paul.bouagnon@ni.com
310 957 1680

Ingo Földvári

Will Denman
Regional Sales Manager
California
will.denman@ni.com
408 610 6966

Cameron Schaefer
Field Engineer
Southern California - Orange County
cameron.schaefer@ni.com
817 371 5570

Jason Marks
Field Engineer - Milpitas and Fremont
Northern California
jason.marks@ni.com
408 806 9090

Zach Collins

Adam Wooderson

Kyle Mozdyn

Glenn Manlongat

Conan McHugh

Thaison Verasiri

Arves Stolpe

Dave Thompson

Chris Grabski

Maggie Shaughnessy

Paul Bouagnon

Cameron Schaefer

Jason Marks

Will Denman
Technical Sales and Support

California (continued)

Bryan Snarr
Area Sales Manager - Consumer Electronic Accounts
California
bryan.snarr@ni.com
916 202 3233

Felicy Colbron
Technical Sales Representative
California
felicy.colbron@ni.com
512 683 0029

Christian Fritz
Business Development Manager - Embedded Systems
California
christian.fritz@ni.com
512 683 5545

Vanessa Trujillo
Strategic Account Manager
California
vanessa.trujillo@ni.com
714-334-8263

Rey Espinosa
Staff Technical Sales Representative
California
rey.espinosa@ni.com
512 683 0038

Kevin Leduc, District Sales Manager
Aerospace and Defense
kevin.leduc@ni.com | 949 282 4167

John Koontz
Area Sales Manager
Greater Los Angeles
john.koontz@ni.com
805 886 5949

John Hottenroth
Sr. Inside Sales Manager
West, California
john.hottenroth@ni.com
512 683 6247

Shahab Seichi, District Sales Manager
Southern California: San Diego / Inland Empire
shahab.seichi@ni.com | 619 403 7273

Felicy Colbron
Technical Sales Representative
California
felicy.colbron@ni.com
512 683 0029

Jon West, Senior Technical Sales Consultant
California
jon.west@ni.com | 512 683 0032

Robert Sims, Area Sales Manager - N. California
Northern California
robert.sims@ni.com | 669 600 7088

John Hottenroth
Sr. Inside Sales Manager
West, California
john.hottenroth@ni.com
512 683 6247

Christian Fritz
Business Development Manager - Embedded Systems
California
christian.fritz@ni.com
512 683 5545

Alan Loprete
Area Sales Manager
San Diego, Orange County, Inland Empire
alan.loprete@ni.com
301-602-7656

Joe Salazar
Inside Sales Engineer
California
joe.salazar@ni.com
512 683-0061

Fabian Moya, Inside Sales Engineer
California
fabian.moya@ni.com | 512 683 0907

Jordan Randall
Manager, Partner Ecosystems and Services
US-West.
jordan.randall@ni.com
408) 540 8450

Huttington Wagner
Inside Sales Engineer
Southern California
huttington.wagner@ni.com
512 683 0027

Dirk De Mol, Principal Architect
California
dirk.demol@ni.com | 408 610 6975

Charlie Knapp, Field Architect
Southern California
charlie.knapp@ni.com | 714 393 5470

John Hottenroth
Sr. Inside Sales Manager
West, California
john.hottenroth@ni.com
512 683 6247

Ryan Lotz, RF Field Systems Engineer
California
ryan.lotz@ni.com | 510 378 2794

Way Shong, Field Systems Engineer
California
way.shong@ni.com | 408 610 6965

Robert Sims, Area Sales Manager - N. California
Northern California
robert.sims@ni.com | 669 600 7088

Robert Sims, Area Sales Manager - N. California
Northern California
robert.sims@ni.com | 669 600 7088

Josh Yang
Inside Sales Engineer - Consumer Electronic Accounts
California
josh.yang@ni.com
512 683 0188

Robert Sims, Area Sales Manager - N. California
Northern California
robert.sims@ni.com | 669 600 7088

David Garcia, Customer Education Specialist
California and Midwest
david.garcia@ni.com | 512 683 0215

Phillip Biggs
Sr. Field Systems Engineer
California
phillip.biggs@ni.com
512 683 4808
Central West

Ed McConnell
Regional Sales Manager
Greater Denver Area
ed.mcconnell@ni.com
303 665 3503

Joel Garner
Area Sales Manager
Northern Texas, Oklahoma, Arkansas, Kansas
joel.garner@ni.com
972 623 7197

Jared McInelly
Area Sales Manager
Oregon, Washington
jared.mcinelly@ni.com
253 205 1522

Garth Black, Area Sales Manager
Colorado, New Mexico, Wyoming
garth.black@ni.com | 801 309-7826

Doug Kunz
Area Sales Manager
Arizona and New Mexico
doug.kunz@ni.com
480 695-9705

Liz Stice
Area Sales Manager
South Central U.S.
liz.stice@ni.com
512 683 9421
Stay Social and Share Your #NIDays Experience

Follow us on Twitter
@niglobal
Get real-time updates and valuable conference information from NI staff. Also remember to search #NIDays to see what your colleagues are saying.

Connect with us on Facebook
facebook.com/nationalinstruments
Want to be friends? Stay up to date on conference news, and be the first to hear company announcements by “liking” NI on Facebook.

Follow us on LinkedIn
linkedin.com/company/national-instruments
Making a lot of new contacts at NIDays? Build your network of connections on LinkedIn and exchange information, ideas, and professional opportunities. Follow the NI company page on LinkedIn to receive conference updates.

Watch us on YouTube
youtube.com/nationalinstruments
View videos by NI staff of cool product demonstrations from the exhibition area.

Subscribe to our feeds
ni.com/rss
NI RSS feeds allow you to receive notifications of new and updated content on ni.com. Choose from over 50 topics to customize your feed.